RECEIVING INSPECTION AT MIT

| ITEM | TEST | NDE | DATA REVIEW | 100% VISUAL INSPECT | MEASURE DIMEN- SIONS | CHEMICAL ANALYSIS |
|---------------------------|------------|----------------|----------------|---------------------------|----------------------------|--------------------------------------|
| EEE DISCRETES | 100% | N/A | YES | YES | NO | N/A |
| MICROCIRCUITS | <u>7</u> / | N/A | YES | YES | NO | N/A |
| MECHANICAL PARTS | NO | YES <u>1</u> / | YES | YES | YES <u>8</u> / | YES <u>1</u> / |
| FABRICATED | | | | | | |
| MECHANICAL PARTS | NO | YES <u>1</u> / | YES | YES | SAMPLE <u>2</u> / | NO <u>3</u> / |
| FABRICATED | | | | | | |
| ASSEMBLIES | NO | NO | YES | YES | NO | NO |
| FASTENERS | | | | | | |
| (<140,000 psi) <u>4</u> / | NO | YES <u>1</u> / | YES | YES | NO | NO |
| METALLIC | | | | | | |
| RAW MATERIALS | NO | N/A | YES | YES | NO | YES <u>1</u> / <u>5</u> / <u>9</u> / |
| NONMETALLIC | | | | | | |
| RAW MATERIALS | NO | N/A | YES | YES | NO | NO <u>1</u> / <u>9</u> / |
| ADHESIVES | <u>6</u> / | N/A | YES | N/A | N/A | NO <u>1</u> / <u>9</u> / |

- 1/ Testing is performed on fracture critical items only
- 2/ All dimensions are measured and recorded by the Vendor
- $\underline{3}$ / Material is supplied by MIT from bonded stock
- $\underline{4}$ / Fasteners >140,000 psi are not used
- 5/ Done by MIT or an Independent testing laboratory
- 6/ Each adhesive lot (100%), is sample tested for proper cure characteristics
- $\underline{7}/$ PPL and Military devices have 100% GSI. Nonstandards receive 100% MIT S.I.
- $\underline{8}$ / where applicable
- 9/ This is an exception to the PAR

1.1.5 <u>Inspection Status Tag</u>

An Inspection Status Tag, Figure 3-1, is attached to the parts container (or to the material where practical). Information contained on the tag indicates the inspections or test to which that particular group of parts or material has been subjected. The Inspection Status Tag also indicates acceptance of the particular group of parts or material when marked "ACCEPTED" in the appropriate information block, by the inspector. The Inspection Status Tag remains attached to the container in which the items are stored until all parts or materials have been expended.

1.1.6 Reject Tag

Parts, materials, subassemblies, and assemblies submitted for inspection, which fail to meet the inspection criteria, in any way, are rejected. A Reject Tag (Figure 4-1) is prepared and affixed to the rejected material. The rejected material is stored separately from all other material to await further action.

1.1.7 Incoming Electrical Performance Test Data

Electrical tests performed per paragraph 1.1.3 above are recorded on appropriate data sheets. Completed Data sheets are maintained in the Incoming/Receiving files.

1.1.8 Parts Screening Data

Data supplied as part of the purchase requisition for parts and materials, as well as evidence of compliance with screening specifications, are reviewed by the inspector and are kept on file in the Incoming/Receiving files. Critical test data will be reviewed by the appropriate design engineer.

1.1.9 limited Life items

Age sensitive products which have a limited self life shall be recorded on the shelf life tag. The shelf life tag shall be attached to the limited life item. The date of manufactur and the expiration date are also recorded on the product unit package. See Figure 5-1.

1.1.9 <u>limited Life items</u> (continued)

Data which is recorded on the shelf life tag is as follows:

product name
purchase order number
manufacturer
manufacturer's part number
manufacturer's lot code or number
date of manufacture
shelf life and storage conditions
expiration date

1.2 Kit Inspection

Parts and materials which have successfully passed incoming inspection are stored in flight bonded stock awaiting use. When needed for assembly, they are drawn from bonded stock and placed in kits by Quality Assurance. The kits are assembled and inspected before issuance for fabrication, utilizing the latest released parts list. Kit tags are attached to the containers.

The kit tags provide next assembly identification as well as the necessary information for the configuration traceability list.

1.3 In-process Inspection

1.3.1 **Visual**

A visual examination, using both microscope and unaided eye is performed on all fabricated components, assemblies, subassemblies, cable harnesses, and sensors. Criteria for accepting the articles submitted for inspection is established by the "Workmanship Requirements: Inspection Criteria for Electronic Equipment" and the appropriate assembly drawings. The steps in the manufacturing process, at which inspections shall be performed, are shown on the applicable approved Assembly Work Order. These inspections are performed to ensure that unacceptable workmanship, not easily detectable at a later stage of manufacture, is clearly identified so that action to correct the deficiency may be taken in a timely manner.

1.3.2 Electrical

Electrical performance tests are conducted at various stages in the manufacturing process to verify performance of subassemblies or assemblies. These tests shall be performed in accordance with applicable released test procedures.

1.3.3 **Documentation**

At the subassembly and assembly level, the results of all in-process inspections, tests, acceptance, or rejection, along with amplifying remarks, are recorded in the AWO. Discrepancies are recorded in the fault log. The completed Fault Log is attached to the applicable assembly work order. Inspection sign off on the Assembly Work Order is made only after acceptance. Those measurements required by the applicable test procedure are recorded on appropriate data sheets. Completed data sheets are maintained in the equipment documentation file.

1.3.4 Component Inprocess Inspection and Tests

As the functionally grouped major subassemblies begin to take on the form of a complete experiment, a Flight Assembly/History Log is started. The log book shall contain a record, in chronologic form, of all inspections, tests, operating time, problems, failures, repairs, serial numbers, weights and any other information useful in compiling a history on the particular experiment. The Flight Assembly/History Log shall be maintained by the Individual responsible for the hardware, and will remain with the experiment. The Log shall be reviewed from time to time by the Quality Assurance Group to verify that entries are complete, and up to date.

INCOMING INSPECTION REPORT

- 2.0 INSTRUCTIONS FOR COMPLETING THE INCOMING INSPECTION REPORT (FIGURE 2-1)
- **2.1 Project** Abbreviated form of the project name; i.e. XTE, Astro-D, AXAF etc.
- **Part Name** Noun name of part; i.e. Diode, transistor, I.C., bracket, housing, connector, power supply, detector, etc..
- **2.3** Part No. Part number which is assigned by MIT/CSR
- 2.4 <u>Distr / Mfr</u> Distributor and Manufacturer from whom the item is procured.
- **Lot Code** The lot code/lot date code shall be as it appears on the manufacturers documentation (if applicable).
- **P.O.Number** The purchase order number by which the parts were procured.
- **2.7 Date Rec** The date on which MIT/CSR receives the part or shipment.
- **Quantity** The total of parts in a particular shipment, except where more than one lot code/lot date code is received. A separate inspection report will be initiated for each lot.
- **Test Procedure No.** The number assigned to the written electrical test procedure by which the part is to be tested (if applicable).
- **2.10** Manufacturer's P/N Part number which is assigned by the part manufacturer.
- **2.11 Documentation** Screening data, test data, or other data required by the purchase order will be reviewed by the inspector. If complete and satisfactory, the inspector shall stamp or initial the space provided.

- **2.12 Serial Number** The serial number marked on the part, material, subassembly, or assembly, which clearly denotes its individual identity when compared with parts of the same type, lot, and part number.
- 2.13 <u>Visual</u> Mark "accepted" or "rejected" as determined by the requirements.
- **2.14 Electrical** Mark "accepted" or "rejected" as determined by the requirements.
- 2.15 **Comments** Self explanatory.

Incoming Inspection Report

Center for Space Reserarch
Massachusetts Institute of Technology

| Project: | | Part Name: | | | Part No.: | |
|---------------------|-------|----------------|------------|----------|-----------|--|
| Distr./Mfr.: | | | | | Lot Code: | |
| P.O. No.: Date Rec: | | | ; ; | | Quantity: | |
| Test Procedure No: | | Documentation: | | | | |
| SERIAL No. | VISUA | AL | ELECTRICAL | COMMENTS | | |
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Incoming Inspection Report

Center for Space Reserarch

Massachusetts Institute of Technology

PARTS

| Project: | | Part Name: | | | | Part No.: | | | |
|--------------|--------|------------|-------|--------|-----------|------------|----------|--|--|
| Distr./Mfr.: | | | | | Lot Code: | | | | |
| P.O. No.: | | | | | Date Rec: | | | | |
| | | | | | cun | mentation: | | | |
| SERIAL No. | VISUAL | ELECT. | QTY | QTY | (| QTY | COMMENTS | | |
| | | | RCV'D | ACCEPT | RE | JECT | | | |
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THE INCOMING INSPECTION STATUS TAG

- 3.0 INSTRUCTIONS FOR COMPLETING THE INCOMING INSPECTION STATUS TAG (FIGURE 3-1)
- **3.1 Project** Abbreviated form of the project, i.e. XTE, AXAF, Astro-D, etc.
- **3.2 Manufacturer**. Manufacturer from whom the item is procured.
- **3.3** MIT No. A part or drawing number which is assigned by MIT/CSR.
- **3.4 Mfg No.** The part, item, or assembly number assigned by the manufacturer.
- **Lot.** The lot code shall be as it appears on the manufacturer's documentation (if applicable).
- **P.O. Number**. The purchase order number by which the item was procured.
- **Date Received.** The date on which MIT/CSR receives the part, or shipment of parts.
- **Quantity**. The total number of parts in a particular shipment, except where more than one lot code is received. A separate inspection report will be initiated for each lot code when practical.
- **3.9 Part Name** Noun name of part; i.e. Diode, transistor, I.C., bracket, housing, connector, power supply, detector, etc..
- **3.10 Date.** Enter the date the visual inspection was performed.
- **3.11** By . Inspector's stamp or signature.

- **3.12 Date**. Enter the date the electrical testing was performed.
- **3.13 By**. The inspector's stamp or signature.
- **3.14 Date**. Enter the date the screening was completed.
- 3.15 By. Inspector's stamp or signature.
- **3.16** Remarks. Special instructions; i.e. Electrostatic sensitive, refrigerate, store flat, radioactive, do not freeze, use before date, etc.

| Incoming Inspection Status Tag MASSACHUSETTS INSTITUTE OF TECHNOLOGY CENTER FOR SPACE RESEARCH | | | | | |
|--|----------|--|--|--|--|
| Project | MFG. | | | | |
| MIT No. | MFG No. | | | | |
| Lot | P.O. No. | | | | |
| Date Rec'd. | QTY. | | | | |
| Part Name | · | | | | |
| Visual Inspection | | | | | |
| Date | ate By | | | | |
| Electrical Test | | | | | |
| Date | Ву | | | | |
| Screening Completed | | | | | |
| Date | Ву | | | | |
| Remarks: | | | | | |
| | | | | | |

Figure 3-1

REJECT TAG

- 4.0 INSTRUCTIONS FOR COMPLETING THE REJECT TAG (FIGURE 41)
- **4.1 Project** Abbreviated name of the project, i.e. XTE, AXAF, Astro-D, etc.
- **4.2 Date**. Date material was rejected.
- **4.3 Part Name**. Diode, resistor, transistor, etc..
- **4.4 Part No.** The part or drawing number assigned by MIT/CSR.
- **4.5** <u>Inspection Report Date</u>. The "date received" as recorded on the inspection report on which the material was rejected.
- **Reason for Rejection**. Brief summary; broken lead, improper marking, void in seal, etc.
- **4.7 <u>Disposition</u>**. Awaiting engineering review, MRB action, Return to Vendor (RTV), scrap, etc.
- **4.8 Inspector**. The inspector's stamp or signature rejecting the material.

REJECT TAG

CENTER FOR SPACE RESEARCH MASSACHUSETTS INSTITUTE OF TECHNOLOGY

| PROJECT | _DATE |
|------------------------|-------|
| PART NAMEPART NO | |
| INSPECTION REPORT DATE | |
| REASON FOR REJECTION | |
| | |
| DISPOSITION | |
| SIGNATURE | |

SHELF LIFE TAG

CENTER FOR SPACE RESEARCH MASSACHUSETTS INSTITUTE OF TECHNOLOGY

| PRODUCT NAME |
|---------------------|
| PURCHASE ORDER NO |
| MANUFACTURER |
| MFGR'S P/N |
| MFGR'S LOT CODE |
| DATE OF MANUFACTURE |
| SHELF LIFE |
| STORAGE CONDITIONS |
| EXPIRATION DATE |
| SIGNATURE |
| DATE RCV'D @ MIT |